Search Notes



_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/055,454	HAN ET AL.	
	Examiner	Art Unit	
	CHUONG T HO	2664	

	SEARCHED		
Class	Subclass	Date	Examiner
370 370 370	412 1 235 1 252 1	09/19/00	5 CH
370	235.1		
709	229		
709	234		
370	229 r		
370	230		
370	2318		
370	232 ×		
370	\$35 قىي		
370	23 H×		
370	413×		
370	ルバファ		
370	429 \$		
709	235		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	412	09/19/05	CH
370	235		
370	252		
709	229		
709	234		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
WEST (TEXT SEARCH) (CLASS SEARCH) EAST STN		CH	
IEEE Consulting with wellington Chin SPE AU 2664	09/21/05	CH	
·			
·			
		·	

Search Notes



Application/Control	No.
10/055 454	

Applicant(s)/Patent under Reexamination
HAN ET AL.

CHUONG T. HO

Examiner

2664

Art Unit

•	SEARCHED			
Class	Subclass	Date	Examiner	
370	235	09/19/05	CH	
370	235.1)		
370	371			
710	52			
710	53			
710	54			
710	56			
710	57			
709	213			
			•	

INTERFERENCE SEARCHED			
Class	Subclass	Date /	Examiner
370	೩૩-೬	09/19/0	5 01
370	<i>233</i>		
370	234		
370	429	1	
370	413		

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
•		
·		
	·	
· 		
	!	